

### 12500 TI Boulevard, MS 8640, Dallas, Texas 75243

# PCN#20200218000.2B Qualify TI Chengdu as an additional Assembly site for select devices Change Notification / Sample Request

Date: September 01, 2020

**To:** Digi-Key PCN

Dear Customer:

**Revision B** is to update the Wettable flank design for TI Chengdu in the description of change section.

This is an announcement of change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

Texas Instruments requires acknowledgement of receipt of this notification within **30** days of the date of this notice. If samples or additional data are required, requests must be received within 30 days of acknowledgement as samples are not built ahead of the change. You may contact the PCN Manager or your local Field Sales Representative to acknowledge this PCN and request samples or additional data.

The changes discussed within this PCN will not take effect until TI receives written customer approval. In order to assure continuity of supply, customer approval is requested no later than 1 month prior to the proposed 1<sup>st</sup> ship date indicated on the following pages.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Team (<u>PCN ww admin team@list.ti.com</u>). For sample requests or sample related questions, contact your field sales representative.

Sincerely,

PCN Team SC Business Services

# 20200218000B Attachment: 1

# **Products Affected:**

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

DEVICE	<b>CUSTOMER PART NUMBER</b>
DRV8702DQRHBRQ1	null
DRV8702DQRHBTQ1	null
DRV8702QRHBRQ1	null
DRV8702QRHBTQ1	null
DRV8703DQRHBTQ1	null
DRV8703QRHBRQ1	null
DRV8703QRHBTQ1	null
DRV8703DQRHBRQ1	null

Technical details of this Product Change follow on the next page(s).

PCN Number: 20200218000.2B PCN Dat							Date:	Sept. 1, 2020	
Title: Qualify TI Chengdu as an additional Assembly site for select devices									es
Cus	stome	er Contact:	PCN Manager		Dept:	Quality Ser	rvices		
Cha	ange '	Туре:							
Assembly Site					Design			Wafe	er Bump Site
Assembly Process				Data She	eet		Wafe	er Bump Material	
Assembly Materials				Part num	nber change		Wafe	er Bump Process	
				Test Site			Wafe	er Fab Site	
Packing/Shipping/Labeling					Test Prod	cess		Wafe	er Fab Materials
								Wafe	er Fab Process

# **PCN Details**

# **Description of Change:**

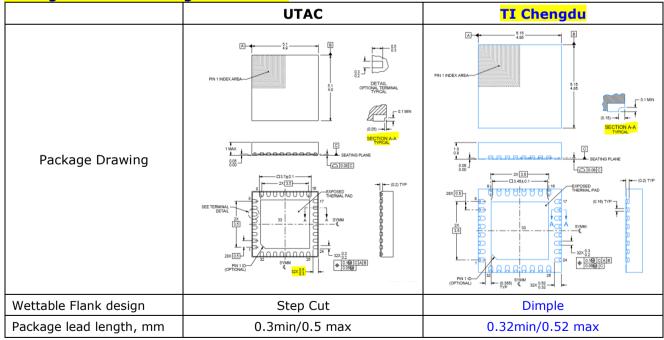
**Revision B** is to update the Wettable flank design for TI Chengdu (Section A-A: Minimum dimple height from 130um to 100 um).

Texas Instruments is pleased to announce the qualification of TI Chengdu as additional Assembly Site for Select Devices listed in the "Product Affected" Section. Material differences are as follows.

#### **Material Differences:**

	UTAC	TI Chengdu
Mount compound	Ablebond 8600	CRM-1076NS
Leadframe finish	Matte Sn	NiPdAu

Package Outline Drawing Differences:

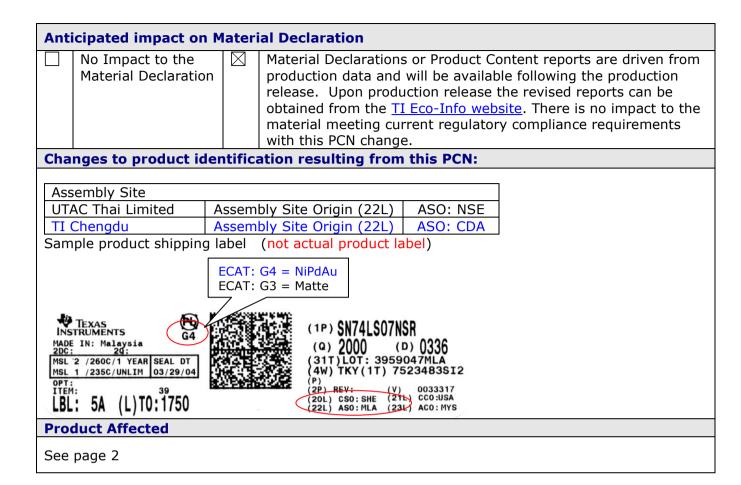


# **Reason for Change:**

Continuity of Supply

Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):

None



# **Qualification Report**

Automotive New Product Qualification Summary (As per AEC-Q100 and JEDEC Guidelines) Approve Date 12-Feb-2020

### **Product Attributes**

Attributes	Qual Device: DRV8702QRHBRQ1	Qual Device: DRV8703QRHBRQ1
Operating Temp Range	-40 to +125 C	-40 to +125 C
Automotive Grade Level	Grade 1	Grade 1
Product Function	Power Management	Power Management
Die Attributes	-	-
Wafer Fab Supplier	RFAB	RFAB
Wafer Diameter (mm)	300	300
Wafer Process Technology	LBC8	LBC8
Wafer Process ID	LBC8	LBC8
Die Revision	Α	Α
Die Size (L,W) (mm)	2.05 X 2.21	2.05 X 2.21
Die Size (H) (mils)	10.5	10.5
Die Gate Length (nm)	-	-
Number of Metal Layers	3	3
Metal Composition	-	-
Die Passivation Material and Thickness	-	-
Final Polyimide	-	-

Attributes	Qual Device: <u>DRV8702QRHBRQ1</u>	Qual Device: <u>DRV8703QRHBRQ1</u>
Backgrind	Mechanical	Mechanical
Die Separation Method	-	-
Package Attributes	-	-
Assembly Site	CDAT	CDAT
Package Type	RHB	RHB
Package Designator	RHB	RHB
Ball/Lead Count	32	32
Package Size (mils)	196.85 X 196.85	196.85 X 196.85
Body Thickness (mils)	35.43	35.43
Ball/Lead Pitch (mils)	19.68	19.68
Die Attach Supplier Name	SUMITOMO	SUMITOMO
Die Attach Supplier Number	CRM-1076NS	CRM-1076NS
Die Attach Material ID	4207123-0002	4207123-0002
Die Attach Method	Epoxy Dispense	Epoxy Dispense
Mold Compound Supplier Name	SUMITOMO	SUMITOMO
Mold Compound Supplier Number	EME-G700LTD-S	EME-G700LTD-S
Mold Compound ID	4222198-0023	4222198-0023
Flammability Rating	UL 94 V-0	UL 94 V-0
Wire Bond Material	PCC	PCC
Wire Bond Diameter (mils)	1.3	1.3
Type of Wire Bond	-	-
Lead Frame Pad Size (mils)	-	-
Lead Frame Material	Cu	Cu
Leadframe Plating Composition	NiPdAu	NiPdAu

- QBS: Qual By Similarity
- Qual Device DRV8703QRHBRQ1 is qualified at LEVEL2-260C
- Qual Device DRV8702QRHBRQ1 is qualified at LEVEL2-260C

# **Qualification Results**

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	#	Test Spec	Min Lot Qty	SS/Lot	Test Name / Condition	Duration	Qual Device: DRV8702QRHBRQ1	Qual Device: DRV8703QRHBRQ1
	Test	Group A – A	cceler	ated Envi	ronment Stress T	ests		
PC	A1	-	3	22	SAM Analysis, Pre Stress	Completed	-	3/66/0
PC	A1	JEDEC J- STD-020 JESD22- A113	3	77	Preconditioning	Level 2- 260C	-	No fails
PC	A1	-	3	22	SAM Analysis, Post Stress	Completed	-	3/66/0
HAST	A2	JEDEC JESD22- A110	3	77	Biased HAST, 130C/85%RH	96 Hours	-	3/240/0
HAST	A2	-	3	1	Cross Section, Post bHAST 96 Hours	Completed	-	3/3/0
HAST	A2	-	3	30	Wire Bond Shear, Post bHast, 96 Hours	Wires	-	3/90/0
HAST	A2	-	3	30	Bond Pull over Stitch, post bHAST, 96	Wires	-	3/90/0

Туре	#	Test Spec	Min Lot	SS/Lot	Test Name / Condition	Duration	Qual Device: DRV8702QRHBRQ1	Qual Device: DRV8703QRHBRQ1
		Орсс	Qty				DIT VOTOZ QITTI DIT Q T	<u>DRV0703@RIIBR@T</u>
HAST	A2	-	3	30	Hours  Bond Pull over Ball, Post bHAST, 96 Hours	Wires	-	3/90/0
HAST	A2	JEDEC JESD22- A110	3	70	Biased HAST, 130C/85%RH	192 Hours	-	3/210/0
HAST	A2	-	3	1	Cross Section, Post bHAST 192 Hours	Completed	-	3/3/0
HAST	A2	-	3	22	SAM Analysis, Post bHAST, 192 Hours	Completed	-	3/66/0
HAST	A2	-	3	30	Wire Bond Shear, Post bHast, 192 Hours	Wires	-	3/90/0
HAST	A2	-	3	30	Bond Pull over Stitch, post bHAST, 192 Hours	Wires	-	3/90/0
HAST	A2	-	3	30	Bond Pull over Ball, Post bHAST, 192 Hours	Wires	-	3/90/0
TC	A4	JEDEC JESD22- A104 and Appendix 3	3	77	Temperature Cycle, - 65/150C	500 Cycles	-	3/298/0
тс	A4	-	3	1	Cross Section, Post T/C 500 Cycles	Completed	-	3/3/0
TC	A4	-	3	22	SAM Analysis, Post T/C, 500 Cycles	Completed	-	3/66/0
TC	A4	-	3	30	Wire Bond Shear, Post T/C 500 Cycles	Wires	-	3/90/0
TC	A4	1	3	30	Bond Pull over Stitch Post T/C 500 Cycles	Wires	-	3/90/0
тс	A4	-	3	30	Bond Pull over Ball Post T/C 500 Cycles	Wires	-	3/90/0
TC	A4	JEDEC JESD22- A104 and Appendix 3	3	70	Temperature Cycle, - 65/150C	1000 Cycles	-	3/230/1*
TC	A4	-	3	1	Cross Section, Post T/C 1000 Cycles	Completed	-	3/3/0
тс	A4	-	3	22	SAM Analysis, Post T/C, 1000 Cycles	Completed	-	3/66/0

Туре	#	Test Spec	Min Lot Qty	SS/Lot	Test Name / Condition	Duration	Qual Device: DRV8702QRHBRQ1	Qual Device: DRV8703QRHBRQ1
TC	A4	,	3	30	Wire Bond Shear, Post T/C 1000 Cycles	Wires	-	3/90/0
TC	A4	ı	3	30	Bond Pull over Stitch, Post T/C, 1000 Cycles	Wires	-	3/90/0
тс	A4	-	3	30	Bond Pull over Ball, Post T/C, 1000 Cycles	Wires	-	3/90/0
PTC	A5	JEDEC JESD22- A105	1	45	Power Temperature Cycle -40/125C	1000 Cycles	-	-
PTC	A5	JEDEC JESD22- A105	1	45	Power Temperature Cycle -40/125C	2000 Cycles	-	-
HTSL	A6	JEDEC JESD22- A103	3	45	High Temp Storage Bake 150C	1000 Hours	-	3/138/0
HTSL	A6	ı	3	1	Cross Section, Post HTSL 1000 Hours	Completed	-	3/3/0
HTSL	A6	JEDEC JESD22- A103	3	44	High Temp Storage Bake 150C	2000 Hours	-	3/135/0
HTSL	A6	-	3	1	Cross Section, Post HTSL 2000 Hours	Completed	-	3/3/0

### A1 (PC): Preconditioning:

Performed for THB, Biased HAST, AC, uHAST & TC samples, as applicable.

### **Ambient Operating Temperature by Automotive Grade Level:**

Grade 0 (or E): -40C to +150C Grade 1 (or Q): -40C to +125C Grade 2 (or T): -40C to +105C Grade 3 (or I): -40C to +85C

### E1 (TEST): Electrical test temperatures of Qual samples (High temperature according to Grade level):

Room/Hot/Cold: HTOL, ED

 ${\sf Room/Hot: THB\,/\,HAST,\,TC\,/\,PTC,\,HTSL,\,ELFR,\,ESD\,\&\,LU}$ 

Room: AC/uHAST

\*: 1 TC fail due to EOS not related to TC, 8D available.

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
WW PCN Team	PCN ww admin team@list.ti.com

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